MGSF3442XT1

Preliminary Information

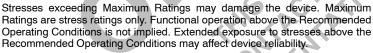
Low R_{DS(on)} Small-Signal MOSFETs Single N-Channel Field Effect Transistors

These miniature surface mount MOSFETs utilize the High Cell Density, HDTMOS process. Low $r_{DS(on)}$ assures minimal power loss and conserves energy, making this device ideal for use in small power management circuitry. Typical applications are dc-dc converters, power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

- Low R_{DS(on)} Provides Higher Efficiency and Extends Battery Life
- Miniature TSOP 6 Surface Mount Package Saves Board Space

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Rating	Symbol	Value	Unit				
Drain-to-Source Voltage	V _{DSS}	20	Vdc				
Gate-to-Source Voltage - Continuous	V _{GS}	± 8.0	Vdc				
Drain Current – Continuous @ $T_A = 25^{\circ}C$ – Pulsed Drain Current ($t_p \le 10 \ \mu s$)	I _D I _{DM}	1.7 20	A				
Total Power Dissipation @ $T_A = 25^{\circ}C$	PD	400	mW				
Operating and Storage Temperature Range	T _J , T _{stg}	– 55 to 150	°C				
Thermal Resistance – Junction-to-Ambient	R _{θJA}	300	°C/W				
Maximum Lead Temperature for Soldering Purposes, for 10 seconds	Т	260	°C				

MAXIMUM RATINGS (T, I = 25°C unless otherwise noted)



ORDERING INFORMATION

Reel Size	Tape Width	Quantity			
7″	8 mm embossed tape	3000			
13″	8 mm embossed tape	10,000			
F	7″	7″ 8 mm embossed tape			

This document contains information on a product under development. ON Semiconductor reserves the right to change or discontinue this product without notice.

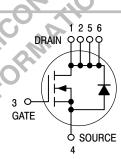


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N-CHANNEL ENHANCEMENT-MODE MOSFET R_{DS(on)} = 58 mΩ (TYP)





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ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS			•			•
Drain-to-Source Breakdown Voltage (V_{GS} = 0 Vdc, I_D = 10 μ A)	9	V _{(BR)DSS}	20	-	-	Vdc
Zero Gate Voltage Drain Current $(V_{DS} = 20 \text{ Vdc}, V_{GS} = 0 \text{ Vdc})$ $(V_{DS} = 20 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 70^{\circ}\text{C})$		I _{DSS}			1.0 5.0	μAdc
Gate-Body Leakage Current (V_{GS} = \pm 8.0 Vdc, V_{DS} = 0)		I _{GSS}	-	-	±100	nAdc
ON CHARACTERISTICS ⁽¹⁾						•
Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 250 \ \mu Adc$)		V _{GS(th)}	0.6	-	-	Vdc
Static Drain-to-Source On-Resistan (V_{GS} = 4.5 Vdc, I_D = 1.7 A) (V_{GS} = 2.5 Vdc, I_D = 1.3 A)	nce	r _{DS(on)}	Ξ	0.058 0.072	0.070 0.095	Ohms
DYNAMIC CHARACTERISTICS					0	
Input Capacitance	(V _{DS} = 5.0 V)	C _{iss}	-	90) - (pF
Output Capacitance	(V _{DS} = 5.0 V)	C _{oss}	-	50	-	
Transfer Capacitance	(V _{DG} = 5.0 V)	C _{rss}	-	10	-	
SWITCHING CHARACTERISTICS ⁽²⁾			< <			
Turn-On Delay Time		t _{d(on)}	Ð	8.0	20	ns
Rise Time	(V _{DD} = 10 Vdc, I _D = 1.0 A,	tr	U	24	40	
Turn-Off Delay Time	V_{GEN} = 10 V, R _L = 10 Ω)	t _{d(off)}		36	60	
Fall Time		tŗ	<u>,O</u> ,	10	20	
Gate Charge	5	QT	-	-	-	nC
SOURCE-DRAIN DIODE CHARACT	ERISTICS					
Continuous Current		I _S	-	-	1.0	А
Pulsed Current		I _{SM}	-	-	5.0	А
Forward Voltage ⁽²⁾		V _{SD}	-	-	1.2	V

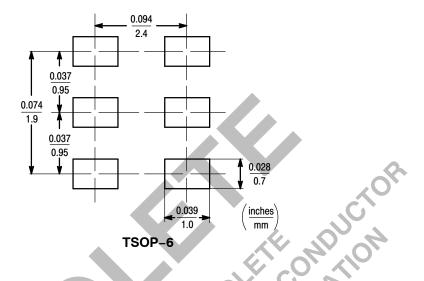
Forward Voltage⁽²⁾
(1) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
(2) Switching characteristics are independent of operating junction temperature.

INFORMATION FOR USING THE TSOP-6 SURFACE MOUNT PACKAGE

MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

Surface mount board layout is a critical portion of the total design. The footprint for the semiconductor packages must be the correct size to insure proper solder connection

interface between the board and the package. With the correct pad geometry, the packages will self align when subjected to a solder reflow process.



TSOP-6 POWER DISSIPATION

The power dissipation of the TSOP-6 is a function of the drain pad size. This can vary from the minimum pad size for soldering to a pad size given for maximum power dissipation. Power dissipation for a surface mount device is determined by $T_{J(max)}$, the maximum rated junction temperature of the die, $R_{\theta JA}$, the thermal resistance from the device junction to ambient, and the operating temperature, T_A . Using the values provided on the data sheet for the TSOP-6 package, P_D can be calculated as follows:

$$P_{D} = \frac{T_{J(max)} - T_{A}}{R_{\theta JA}}$$

The values for the equation are found in the maximum ratings table on the data sheet. Substituting these values into the equation for an ambient temperature T_A of 25°C, one can calculate the power dissipation of the device which in this case is 400 milliwatts.

$$P_D = \frac{150^{\circ}C - 25^{\circ}C}{300^{\circ}C/W} = 400 \text{ milliwatts}$$

The 300°C/W for the TSOP–6 package assumes the use of the recommended footprint on a glass epoxy printed circuit board to achieve a power dissipation of 400 milliwatts. There are other alternatives to achieving higher power dissipation from the TSOP–6 package. Another alternative would be to use a ceramic substrate or an aluminum core board such as Thermal Clad[™]. Using a board material such as Thermal Clad, an aluminum core board, the power dissipation can be doubled using the same footprint.

SOLDERING PRECAUTIONS

The melting temperature of solder is higher than the rated temperature of the device. When the entire device is heated to a high temperature, failure to complete soldering within a short time could result in device failure. Therefore, the following items should always be observed in order to minimize the thermal stress to which the devices are subjected.

Always preheat the device.

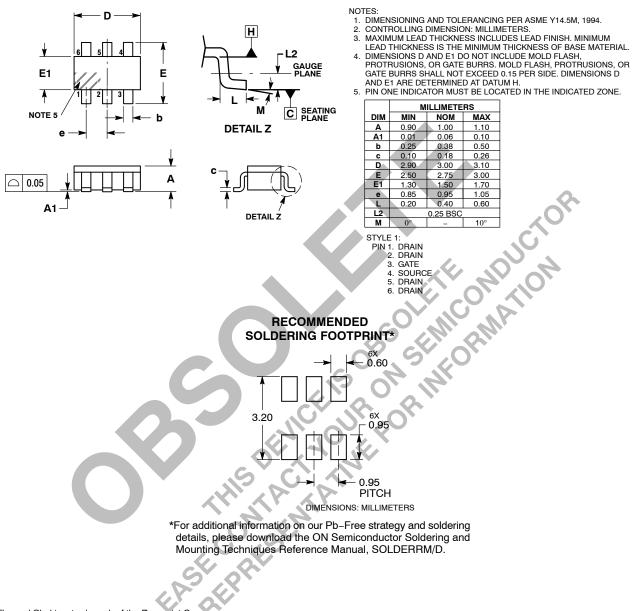
- The delta temperature between the preheat and soldering should be 100°C or less.*
- When preheating and soldering, the temperature of the leads and the case must not exceed the maximum temperature ratings as shown on the data sheet. When using infrared heating with the reflow soldering method, the difference shall be a maximum of 10°C.
- The soldering temperature and time shall not exceed 260°C for more than 10 seconds.
- When shifting from preheating to soldering, the maximum temperature gradient shall be 5°C or less.
- After soldering has been completed, the device should be allowed to cool naturally for at least three minutes. Gradual cooling should be used as the use of forced cooling will increase the temperature gradient and result in latent failure due to mechanical stress.
- Mechanical stress or shock should not be applied during cooling.

* Soldering a device without preheating can cause excessive thermal shock and stress which can result in damage to the device.

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PACKAGE DIMENSIONS

TSOP-6 CASE 318G-02 ISSUE V



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